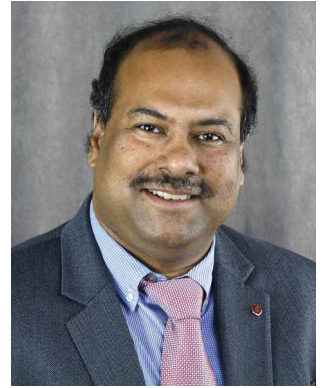


From the EIC

Ethics in Computing



■ **THE ARTICLES IN** this issue are divided into three groups: 1) the first group comprises the Special Issue on Ethics in Computing articles; 2) the second group consists of general interest articles; and 3) additionally, we have a tutorial article in this issue.

The highlight of this issue is the Special Issue on Ethics in Computing. This special issue aims to raise awareness of emerging ethical issues with current and emerging computing technologies and their widespread use. It covers diverse aspects of the theory, practice, experiences, and open challenges related to ethical design, testing, and use of computing platforms. Computing is now ubiquitous. Hence, it can have significant ethical implications, which computing professionals need to carefully consider.

The special issue consists of four highly rated research articles covering a diversity of viewpoints related to ethics in computing. The scope spans the entire silicon ecosystem, from technology, foundry, design, EDA, test, verification, and debugging to in-field deployment, and integration into Internet of Things, cyber-physical systems, and cloud computing

platforms, as well as computing education. We thank the guest editors Sudeep Pasricha and Marilyn Wolf for making this special issue possible.

The general interest articles are titled as follows: 1) “Randomized Testing of RISC-V CPUs Using Direct Instruction Injection”; 2) “Area-Efficient LFSR-Based Stochastic Number Generators With Minimum Correlation”; 3) “Memory Usage Estimation for Dataflow-Model-Based Software Development Methodology”; and 4) “FALCON: An FPGA Emulation Platform for Domain-Specific SoCs (DSSoCs).”

A distinguishable feature of this issue is the tutorial article titled “Furthering Moore’s Law Integration Benefits in the Chiplet Era” by Rob Munoz from Intel.

This issue also contains two conference reports: the 28th IEEE European Test Symposium and the International Symposium on Low-Power Electronics and Design (ISLPED 2023).

Many thanks to Scott Davidson for the Last Byte titled “Losing My Memory.”

I hope you enjoy reading this issue of *IEEE Design&Test*. ■

A handwritten signature in black ink, appearing to read 'Partha Pande', with a stylized flourish at the end.

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